

Title:	Performance report for SiT3372, 204.8 MHz, HCSL		
Type:	Performance report Rev: 1.2		1.2
Orig:		Date:	<b>September 07, 2018</b>

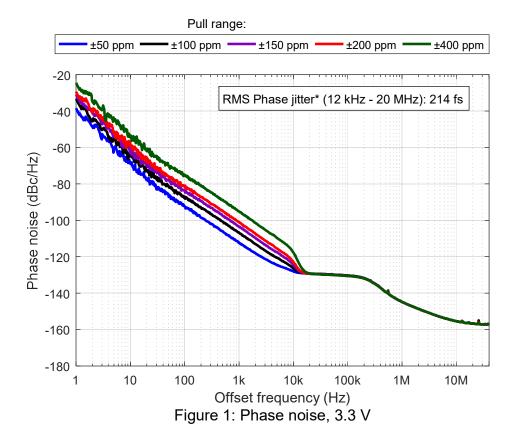
## Performance report for SiT3372 - 204.8 MHz, HCSL

## This performance report contains the following data:

- Phase noise
- Random phase jitter
- Output waveforms
- Pull range linearity
- Frequency stability over temperature
- Period jitter
- Duty cycle
- Rise/Fall time
- Amplitude
- Current consumption



Title:	Performance report for SiT3372, 204.8 MHz, HCSL		
Type:	Performance report	Rev:	1.2
Orig:		Date:	September 07, 2018



\*Integrated phase jitter value applies for ±50 ppm to ±400 ppm pull ranges

Table 1: Phase noise

Phase noise dBc/Hz					
Frequency offset	Pull range (ppm)				
(Hz)	±50	±100	±150	±200	±400
1	-38.4	-33.2	-30.8	-29.4	-24.5
10	-69.0	-64.5	-61.4	-58.3	-54.2
100	-92.5	-87.0	-83.6	-81.1	-75.4
1 K	-112.2	-106.9	-103.5	-101.1	-95.1
10 K	-128.1	-126.4	-124.6	-122.9	-117.7
100 K	-130.3	-130.3	-130.4	-130.5	-130.5
1 M	-144.8	-144.8	-144.9	-144.8	-144.8
10 M	-155.4	-155.4	-155.4	-155.4	-155.4
40 M	-157.3	-157.3	-157.3	-157.3	-157.3

5451 Patrick Henry Drive, Santa Clara, California 95054 • 408.328.4400 • sitime.com

Page 2 of 10



Title:	Performance report for SiT3372, 204.8 MHz, HCSL			
Type:	Performance report Rev: 1.2			
Orig:		Date:	<b>September 07, 2018</b>	

Table 2: Integrated Phase jitter

Darameter	Units	Pull range (ppm)
Parameter	Utills	±50 to ±400
Integrated Phase jitter (1.875 MHz - 20 MHz)	fs, rms	90
Integrated Phase jitter (12 kHz - 20 MHz)	fs, rms	214



Title:	Performance report for SiT3372, 204.8 MHz, HCSL			
Type:	Performance report Rev: 1.2			
Orig:		Date:	September 07, 2018	



Figure 2: Output waveform, 2.5 V



Figure 3: Output waveform, 3.3 V

5451 Patrick Henry Drive, Santa Clara, California 95054 • 408.328.4400 • sitime.com

Page 4 of 10



Title:	Performance report for SiT3372, 204.8 MHz, HCSL		
Type:	Performance report	Rev:	1.2
Orig:		Date:	<b>September 07, 2018</b>

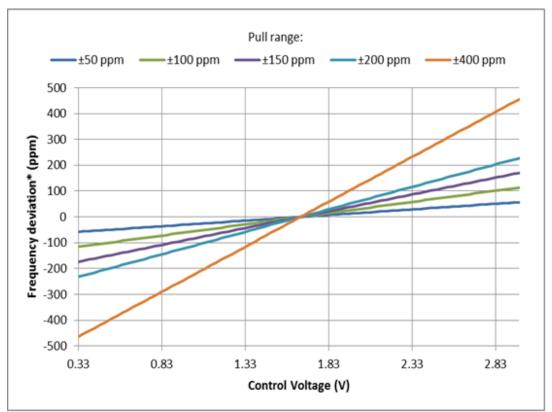


Figure 4: Frequency pull characteristic



Title:	Performance report for SiT3372, 204.8 MHz, HCSL		
Type:	Performance report	Rev:	1.2
Orig:		Date:	<b>September 07, 2018</b>

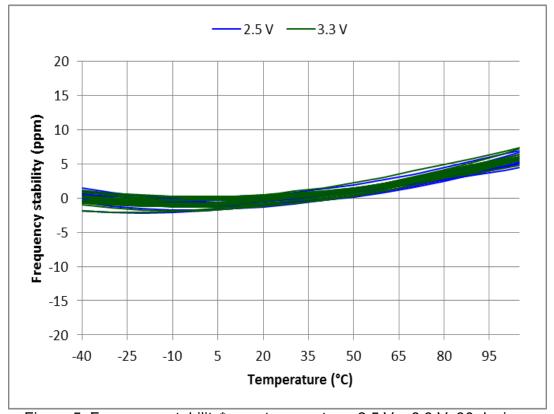


Figure 5: Frequency stability\* over temperature, 2.5 V – 3.3 V, 30 devices

\*SiT3372 frequency stability is independent of output frequency.



Title:	Performance report for SiT3372, 204.8 MHz, HCSL		
Type:	Performance report Rev: 1.2		1.2
Orig:		Date:	<b>September 07, 2018</b>

Table 3: Summary performance data

Parameter	Units	Voltage		
Parameter	Utilits	2.5 V	3.3 V	
Period jitter	ps, rms	1.05	1.06	
Period jitter (sample size 10,000 cycles)	ps, pk-pk	8.07	8.03	
Duty cycle	%	50.0	49.9	
Rise time (20% - 80%)	ps	387	388	
Fall time (80% - 20%)	ps	385	385	
Differential voltage swing	V	1.54	1.62	
Current consumption (no load, output enabled)	mA	83.7	84.4	
Current consumption (no load, output disabled)	mA	56.1	56.1	



Title:	Performance report for SiT3372, 204.8 MHz, HCSL			
Type:	Performance report Rev: 1.2			
Orig:		Date:	<b>September 07, 2018</b>	

## **Test description**

# **Conditions:**

Frequency: 204.8 MHzVDD: 2.5 V, 3.3 V

- Pull range: ±50 ppm, ±100 ppm, ±150 ppm, ±200 ppm, ±400 ppm

- Temperature: 25 °C

## **Equipment:**

Model	Measurement / Purpose
Keysight DSA90604A (6 GHz,	Period jitter, output amplitude, rise/fall time,
20 Gsps)	duty cycle
Keysight 5052B Signal Source	Phase noise, integrated phase jitter
Analyzer	
Keysight 34980A	Power supply current
Keysight E3631A	Power supply
Keysight 53230A	Frequency



Title:	Performance report for SiT3372, 204.8 MHz, HCSL				
Type:	Performance report	Rev:	1.2		
Orig:		Date:	<b>September 07, 2018</b>		

#### Setup

#### Waveform

For waveform parameters measurement (rise/fall time, differential swing, duty cycle), both DUT outputs are terminated with 30  $\Omega$  series and 50  $\Omega$  to GND. Output signals are measured using Keysight 1134B active probe with Keysight N5425B probe head. All measurements are applied to the differential waveform. Figure 6 shows test setup diagram for waveform parameters measurement.

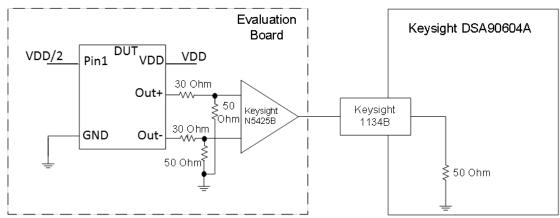


Figure 6. Test setup for measuring waveform parameters (rise/fall time, differential swing, duty cycle)

### **Period Jitter**

For period jitter measurement output is terminated with 30  $\Omega$  series and 50  $\Omega$  to GND at the input of hi-speed comparator (ADCMP581). AC coupled comparator's output is connected to oscilloscope channel. Figure 7 shows test setup diagram for period jitter measurement.

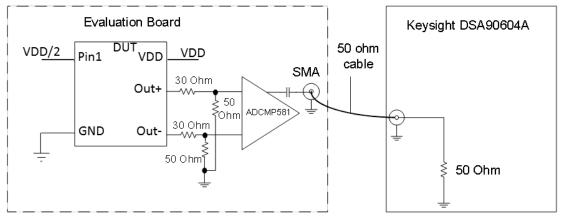


Figure 7. Test setup for measuring period jitter

	Title:	Performance report for SiT3372, 204.8 MHz, HCSL		
<b>Si</b> Time	Type:	Performance report	Rev:	1.2
	Orig:		Date:	<b>September 07, 2018</b>

#### Phase noise

For phase noise measurements, differential signal is converted to single-ended using impedance matching transformer. Transformer's output is connected to measurement instrument. Output is also terminated with 30  $\Omega$  series at the source side. Figure 8 shows test setup diagram for phase noise measurement.

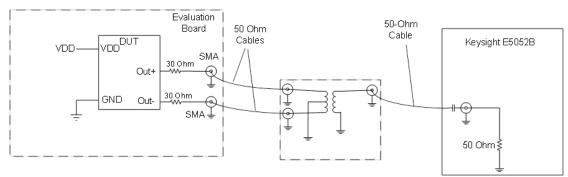


Figure 8. Test setup for measuring phase noise.

#### **Current consumption**

For Current consumption measurement device output is floating. For frequency measurement differential-to-single-ended converter is used.